AFM
(Atomic Force Microscope)

Technology

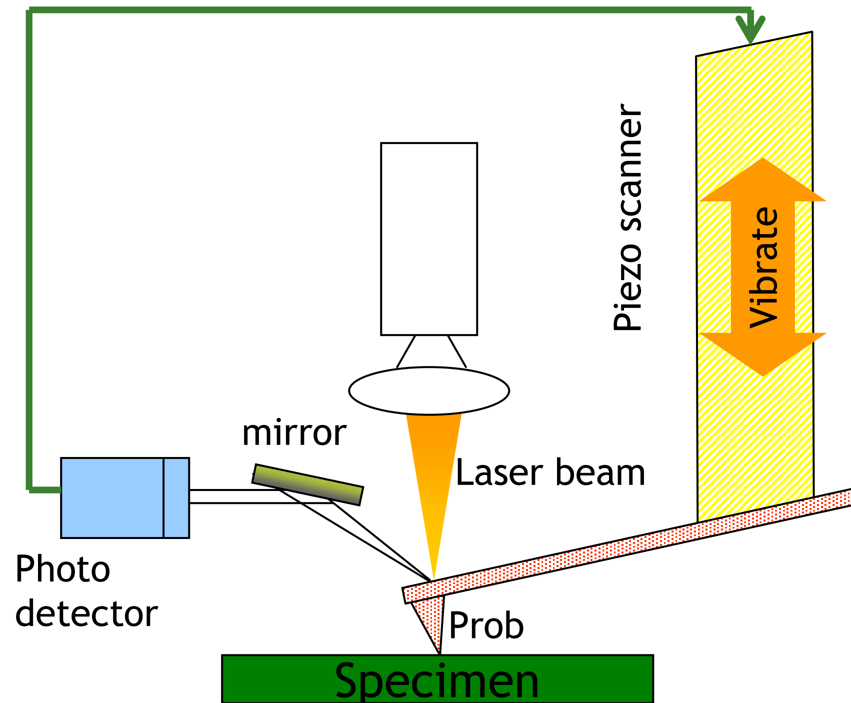
The probe scans the surface of the specimen, keeping the repulsive force between the specimen and the probe at a specific value.

Application

Analysis of the surface profile at the high-resolution
(Resolution for height direction: Sub angstrom level
Analysis of the Surface roughness

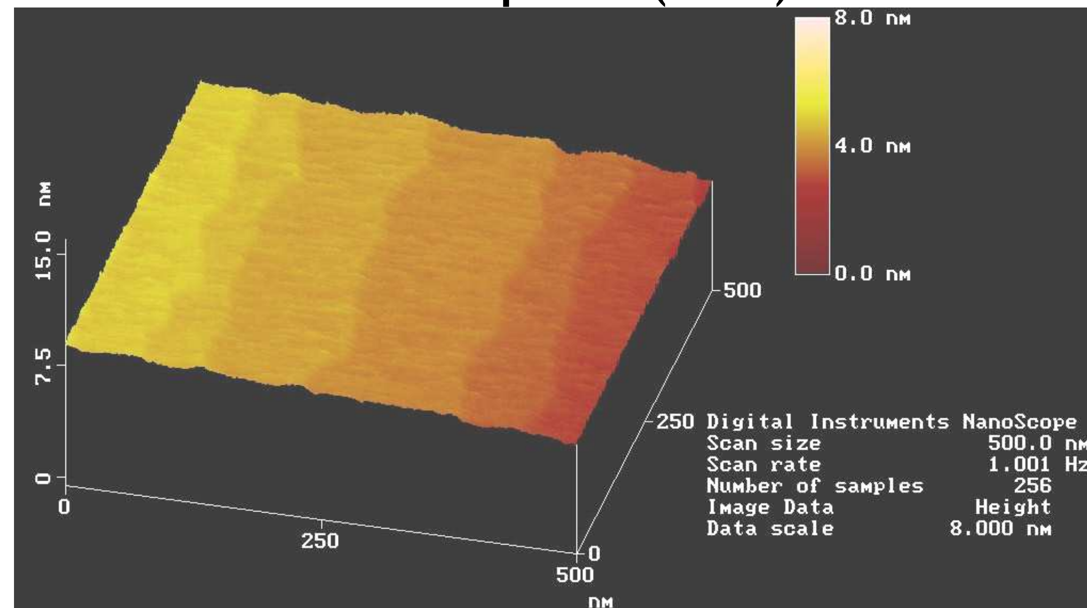
Max scan area	X-Y axis:90um Z axis: 6um
Max specimen size	Diameter:150mm Thickness:12mm

AFM in "Tapping mode"



Example

Monoatomic step - Si(111) surface



Gold standards , height:0.31nm

The method is suitable for…

- Surface roughness of the silicon wafer
- Surface roughness of the spattered film, plating layer
- Measuring the micro gaps in the array of plastic lenses
- Surface profile of the organic material